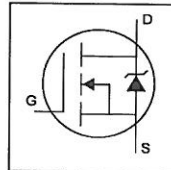


## IRF540N

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic  $dv/dt$  Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

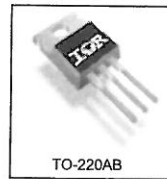


$V_{DS} = 100V$   
 $R_{DS(on)} = 44m\Omega$   
 $I_D = 33A$

### Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



TO-220AB

### Absolute Maximum Ratings

Parameter	Max.	Units
$I_D$ @ $T_C = 25^\circ C$ Continuous Drain Current, $V_{GS}$ @ 10V	33	A
$I_D$ @ $T_C = 100^\circ C$ Continuous Drain Current, $V_{GS}$ @ 10V	23	A
$I_{DM}$ Pulsed Drain Current ①	110	A
$P_D$ @ $T_C = 25^\circ C$ Power Dissipation	130	W
Linear Derating Factor	0.87	W/°C
$V_{GS}$ Gate-to-Source Voltage	± 20	V
$I_{AR}$ Avalanche Current ②	16	A
$E_{AR}$ Repetitive Avalanche Energy ③	13	mJ
$dv/dt$ Peak Diode Recovery $dv/dt$ ④	7.0	V/ns
$T_J$ Operating Junction and Storage Temperature Range	-55 to + 175	°C
Soldering Temperature, for 10 seconds	300 (1.6mm from case)	°C
Mounting torque, 6-32 or M3 screw	10 lbf-in (1.1N-m)	

### Thermal Resistance

Parameter	Typ.	Max.	Units
$R_{\theta JC}$ Junction-to-Case	—	1.15	°C/W
$R_{\theta CS}$ Case-to-Sink, Flat, Greased Surface	0.50	—	°C/W
$R_{\theta JA}$ Junction-to-Ambient	—	62	°C/W

## IRF540N

### Electrical Characteristics @ $T_J = 25^\circ C$ (unless otherwise specified)

Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{DS(BR)}$ Drain-to-Source Breakdown Voltage	100	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{DS(BR)}/\Delta T_J$ Breakdown Voltage Temp. Coefficient	—	0.12	—	V/°C	Reference to $25^\circ C, I_D = 1mA$
$R_{DS(on)}$ Static Drain-to-Source On-Resistance	—	—	44	mΩ	$V_{GS} = 10V, I_D = 16A$ ①
$V_{GS(th)}$ Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$g_{fs}$ Forward Transconductance	21	—	—	S	$V_{DS} = 50V, I_D = 16A$ ②
$I_{DSS}$ Drain-to-Source Leakage Current	—	—	25	μA	$V_{GS} = 100V, V_{DS} = 0V$
$I_{GSS}$ Gate-to-Source Forward Leakage	—	—	100	nA	$V_{DS} = 80V, V_{GS} = 0V, T_J = 150^\circ C$
$I_{GSS}$ Gate-to-Source Reverse Leakage	—	—	-100	nA	$V_{GS} = 20V$
$Q_g$ Total Gate Charge	—	—	71	nC	$V_{DS} = 50V$
$Q_{gs}$ Gate-to-Source Charge	—	—	14	nC	$I_D = 16A$
$Q_{gd}$ Gate-to-Drain ("Miller") Charge	—	—	21	nC	$V_{DS} = 80V$
$t_{d(on)}$ Turn-On Delay Time	—	11	—	ns	$V_{DS} = 10V$ , See Fig. 6 and 13
$t_r$ Rise Time	—	35	—	ns	$V_{DS} = 50V$
$t_{d(off)}$ Turn-Off Delay Time	—	39	—	ns	$I_D = 16A$
$t_f$ Fall Time	—	35	—	ns	$R_G = 5.1\Omega$
$L_D$ Internal Drain Inductance	—	4.5	—	nH	$V_{GS} = 10V$ , See Fig. 10 ④
$L_S$ Internal Source Inductance	—	7.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$C_{iss}$ Input Capacitance	—	1950	—	pF	$V_{DS} = 0V$
$C_{oss}$ Output Capacitance	—	250	—	pF	$V_{DS} = 25V$
$C_{rfs}$ Reverse Transfer Capacitance	—	40	—	pF	$f = 1.0MHz$ , See Fig. 5
$E_{AS}$ Single Pulse Avalanche Energy ⑤	—	700 ⑥	185 ⑥	mJ	$I_{AS} = 16A, L = 1.5mH$

### Source-Drain Ratings and Characteristics

Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$ Continuous Source Current (Body Diode)	—	—	33	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$ Pulsed Source Current (Body Diode) ①	—	—	110	A	
$V_{SD}$ Diode Forward Voltage	—	—	1.2	V	$T_J = 25^\circ C, I_S = 16A, V_{GS} = 0V$ ②
$t_{rr}$ Reverse Recovery Time	—	115	170	ns	$T_J = 25^\circ C, I_F = 16A$
$Q_{rr}$ Reverse Recovery Charge	—	505	760	nC	$di/dt = 100A/\mu s$ ③
$t_{on}$ Forward Turn-On Time	—	—	—	ns	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$ )

#### Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② Starting  $T_J = 25^\circ C, L = 1.5mH$   
 $R_G = 25\Omega, I_{AS} = 16A$ . (See Figure 12)

③  $I_{SD} \leq 16A, di/dt \leq 340A/\mu s, V_{DD} \leq V_{DS(BR)}$   
 $T_J \leq 175^\circ C$

④ Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .

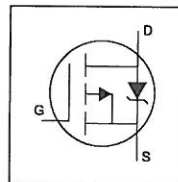
⑤ This is a typical value at device destruction and represents operation outside rated limits.

⑥ This is a calculated value limited to  $T_J = 175^\circ C$ .

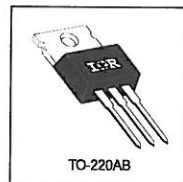
## IRF5305

HEXFET® Power MOSFET

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated



$V_{DS} = -55V$   
 $R_{DS(on)} = 0.06\Omega$   
 $I_D = -31A$



### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

### Absolute Maximum Ratings

Parameter	Max.	Units
$I_D$ @ $T_C = 25^\circ C$	-31	A
$I_D$ @ $T_C = 100^\circ C$	-22	A
$I_{DM}$	-110	A
$P_D$ @ $T_C = 25^\circ C$	110	W
Linear Derating Factor	0.71	W/°C
$V_{GS}$	$\pm 20$	V
$E_{AS}$	280	mJ
$I_{AR}$	-16	A
$E_{AR}$	11	mJ
dv/dt	-5.0	V/ns
$T_J$	-55 to +175	°C
$T_{STG}$		°C
Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
Mounting torque, 6-32 or M3 screw	10 lbf·in (1.1N·m)	

### Thermal Resistance

Parameter	Typ.	Max.	Units
$R_{\theta JC}$	—	1.4	°C/W
$R_{\theta CS}$	0.50	—	°C/W
$R_{\theta JA}$	—	62	°C/W

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## IRF5305

### Electrical Characteristics @ $T_J = 25^\circ C$ (unless otherwise specified)

Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)SS}$	-55	—	—	V	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta V_{(BR)SS}/\Delta T_J$	—	-0.034	—	V/°C	Reference to $25^\circ C, I_D = -1mA$
$R_{DS(on)}$	—	0.06	—	$\Omega$	$V_{GS} = -10V, I_D = -16A$ ①
$V_{GS(th)}$	-2.0	-4.0	—	V	$V_{DS} = V_{GS}, I_D = -250\mu A$
$g_{fs}$	8.0	—	—	S	$V_{DS} = -25V, I_D = -16A$
$I_{DSS}$	—	—	-25	$\mu A$	$V_{DS} = -55V, V_{GS} = 0V$
$I_{GSS}$	—	—	100	nA	$V_{DS} = -44V, V_{GS} = 0V, T_J = 150^\circ C$
$Q_{gs}$	—	—	63	nC	$V_{GS} = 20V$
$Q_{gd}$	—	—	13	nC	$V_{GS} = -20V$
$t_{d(on)}$	—	—	29	ns	$I_D = -16A$
$t_r$	—	—	14	ns	$V_{DS} = -28V$
$t_{d(off)}$	—	—	66	ns	$I_D = -16A$
$t_f$	—	—	39	ns	$R_G = 6.8\Omega$
$L_D$	—	—	63	nH	$R_D = 1.6\Omega$ , See Fig. 10 ②
$L_S$	—	—	7.5	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$C_{iss}$	—	—	1200	pF	$V_{GS} = 0V$
$C_{oss}$	—	—	520	pF	$V_{DS} = -25V$
$C_{rss}$	—	—	250	pF	$f = 1.0MHz$ , See Fig. 5

### Source-Drain Ratings and Characteristics

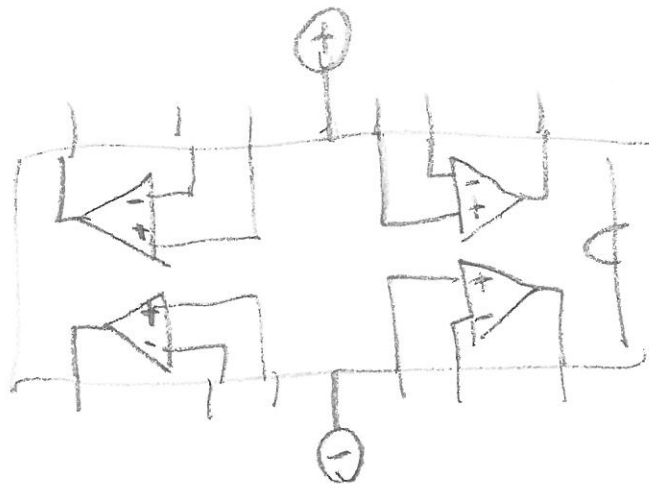
Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	—	—	-31	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	—	—	-110	A	
$V_{SD}$	—	—	-1.3	V	$T_J = 25^\circ C, I_S = -16A, V_{GS} = 0V$ ③
$t_{rr}$	—	71	110	ns	$T_J = 25^\circ C, I_S = -16A$
$Q_{rr}$	—	170	250	nC	$dI/dt = -100A/\mu s$ ④

#### Notes:

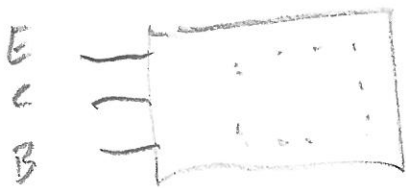
- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)  
②  $V_{DS} = -25V$ , starting  $T_J = 25^\circ C$ ,  $L = 2.1mH$ ,  $R_G = 25\Omega$ ,  $I_{AS} = -16A$ . (See Figure 12)

③  $I_{SD} \leq -16A$ ,  $dI/dt \leq -280A/\mu s$ ,  $V_{DS} \leq V_{(BR)SS}$ ,  $T_J \leq 175^\circ C$

④ Pulse width  $\leq 300\mu s$ ; duty cycle  $\leq 2\%$ .



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